



# VLSI Testing

## 積體電路測試

### ***Logic Built-In Self Test (BIST)***

### ***Part 2: ORA, BIST Architecture\****

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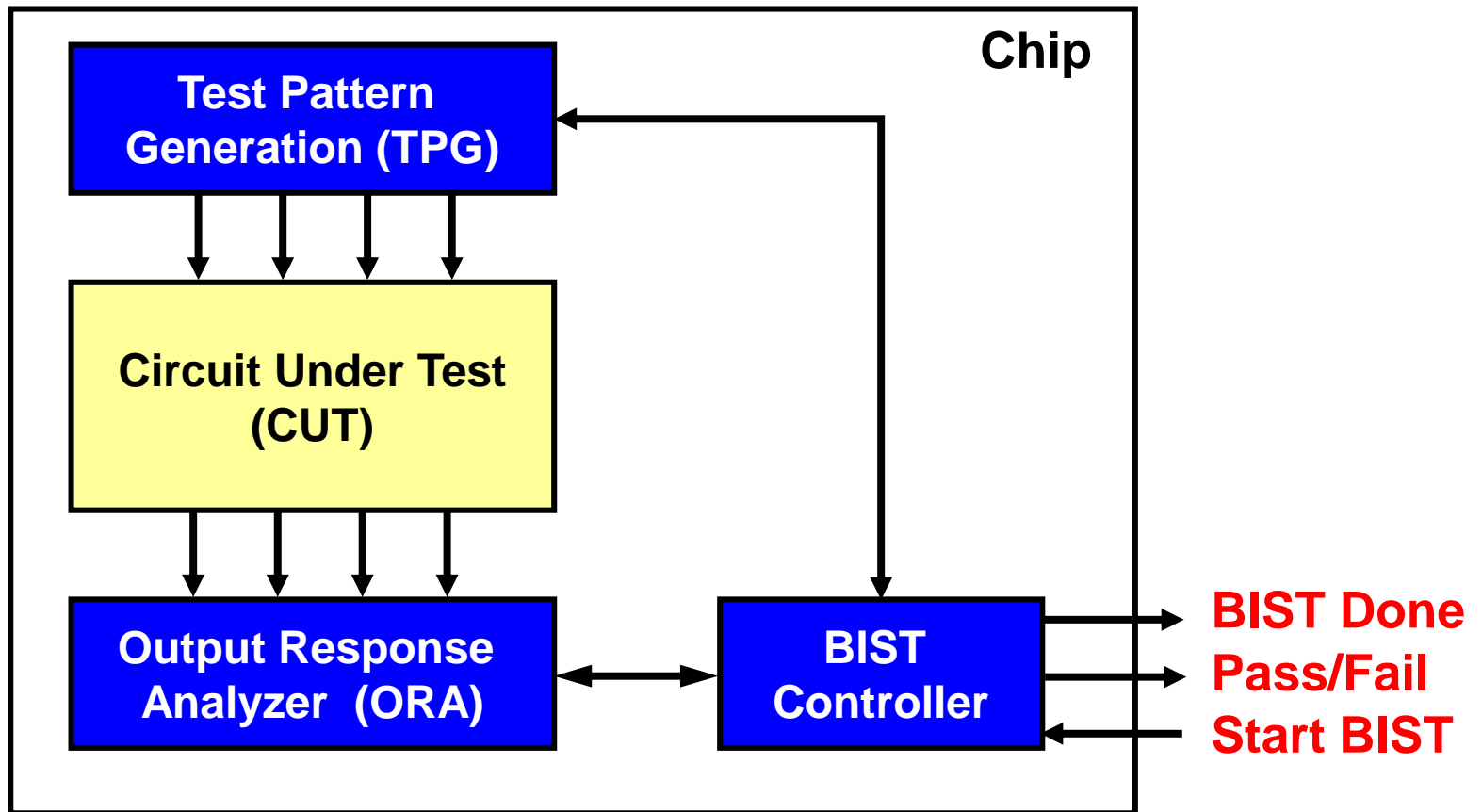
**National Taiwan University**

\* Some pictures are courtesy of Prof. Shi-yu Huang, NTHU

VLSI Test 14.1 © National Taiwan University

# Architecture of BIST (Review)

- Three components: **BIST Controller, TPG, ORA**
- Three I/O Pins: **Start BIST, BIST Done, Pass/Fail**



# Why Am I Learning This?

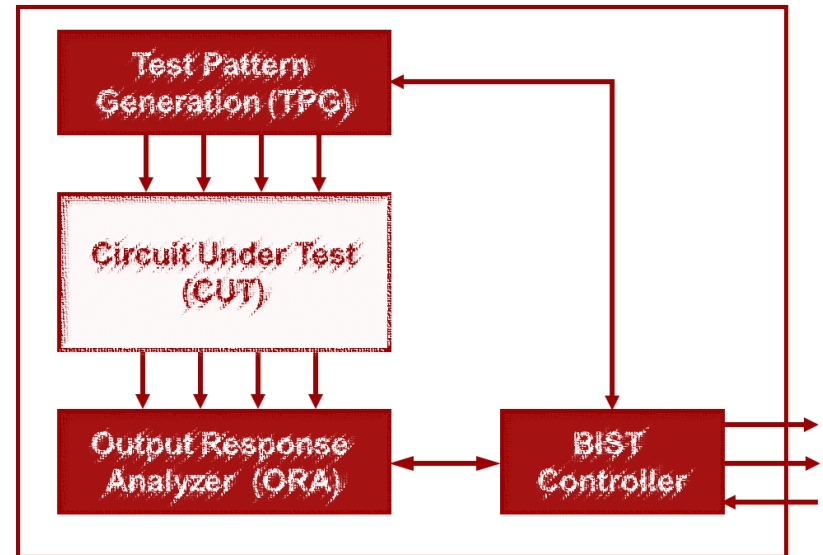
- Output Response Analyzer
  - ◆ Observe CUT output responses on chip
  - ◆ Very small area but correct Pass/Fail decision

***“What the superior man seeks is in himself;  
what the small man seeks is in others.”***

***君子求諸己，小人求諸人  
(Confucius)***

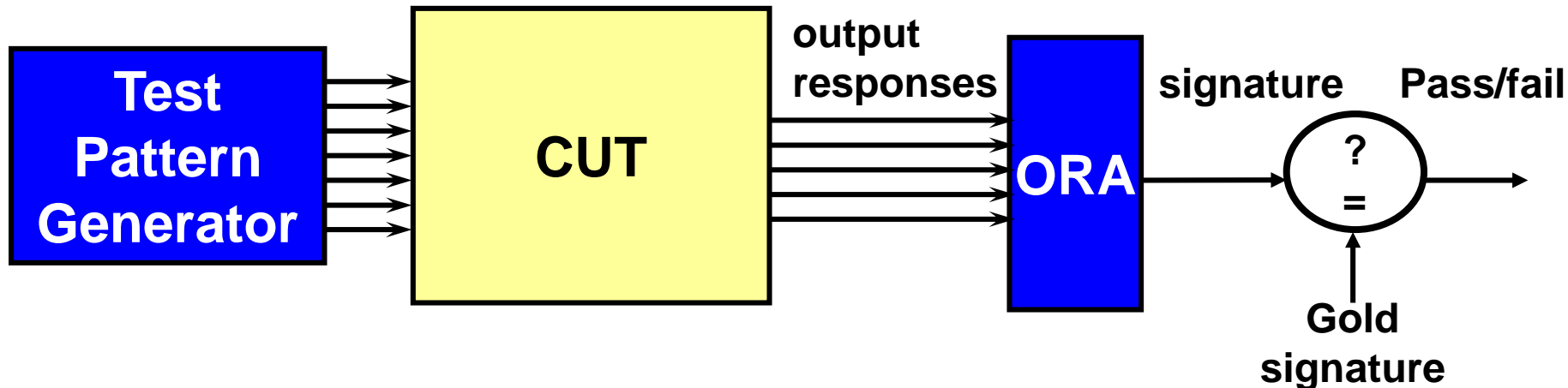
# BIST Part 2

- Part 1
  - ♦ Introduction
  - ♦ Test Pattern Generation
- Part 2
  - ♦ Output Response Analysis
  - ♦ BIST Architecture
  - ♦ Issues with BIST
  - ♦ Conclusions



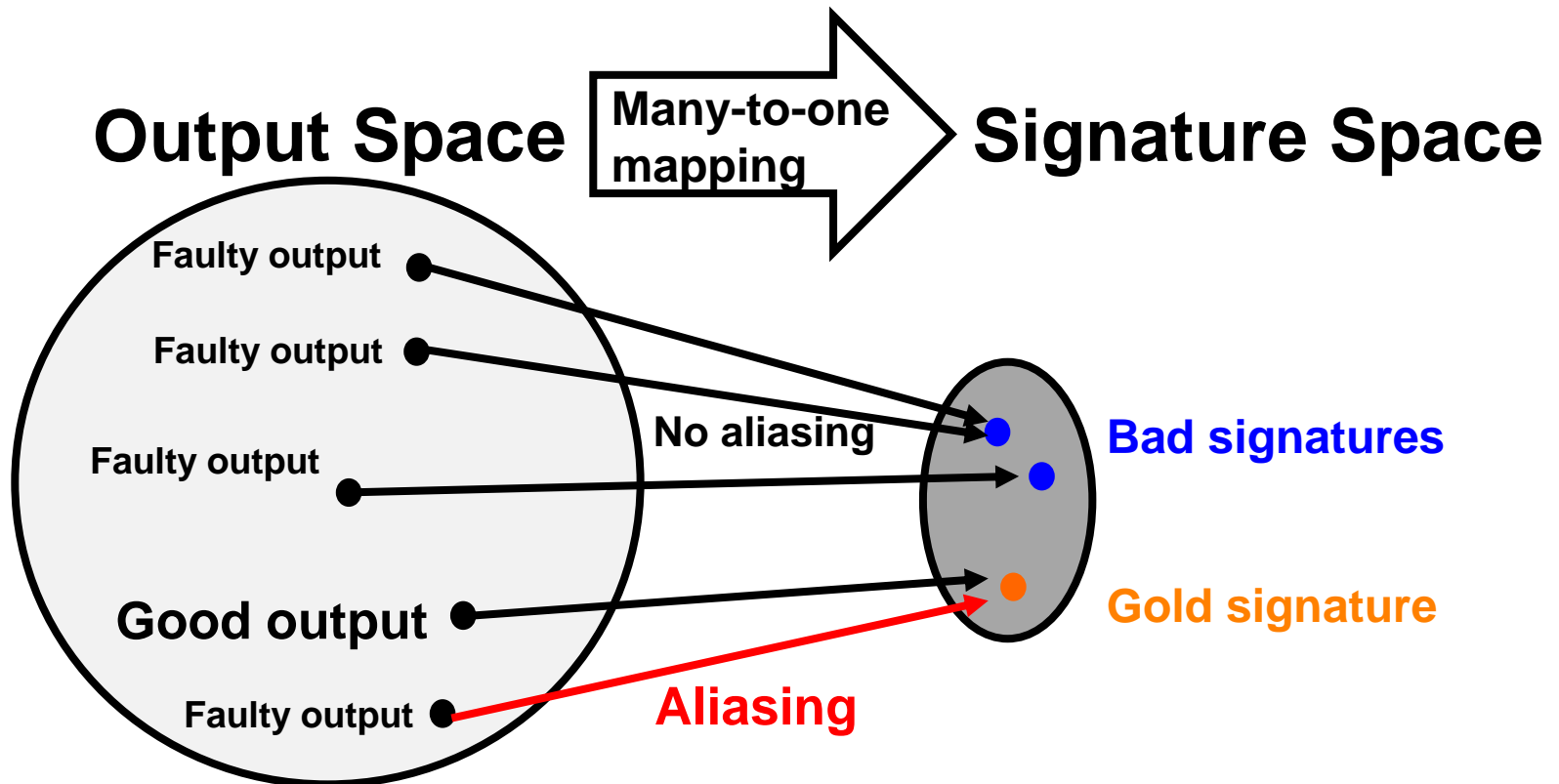
# Output Response Analyzer

- What is ORA?
  - ♦ **Compress** CUT output responses into a small **signature**
  - ♦ Compare signature with **gold signature** to determine pass or fail
  - ♦ ORA also called **signature analyzer**
- What is good ORA? (very difficult to meet all requirements)
  - ♦ 1. Signature as **small** as possible
  - ♦ 2. **Correct Pass/Fail decision** (i.e. **low aliasing**, see next slide)
  - ♦ 3. **Small area**
  - ♦ 4. **Diagnosis support**



# Aliasing

- **Aliasing** occurs when
  - ♦  $\text{signature}_{\text{faulty output}} = \text{signature}_{\text{good output}}$  (*gold signature*)
- Aliasing  $\rightarrow$  Fault coverage loss  $\rightarrow$  **Test escapes**
  - ♦ Defective circuits pass tests (**Very bad!**)



# Probability of Aliasing

- Aliasing depends on many factors:
  - ♦ CUT, faults, test pattern, **ORA structure**
  - ♦ Exact analysis of aliasing difficult
  - ♦ Just **probability analysis** is good enough
- **Probability of Aliasing (PAL)**

$$PAL = \frac{\text{number of faulty outputs that generate gold signature}}{\text{total number of faulty outputs}}$$

- ♦ PAL between 0 and 1. Lower is better.

**Good ORA Requires Low PAL**

# Quiz

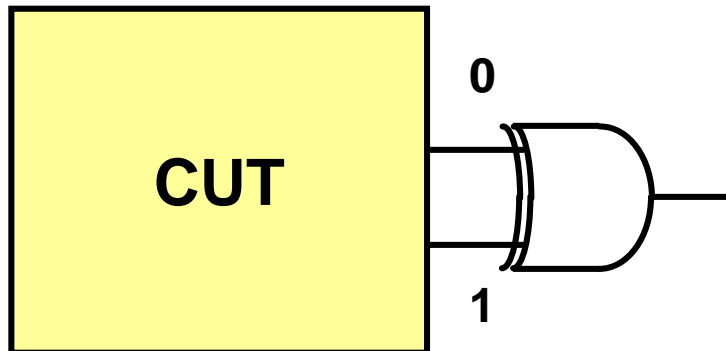
**Q1:** We use OR gate as ORA. Suppose good output is '01', what is gold signature?

**ANS:**

**Q2:** What is PAL of this ORA? Suppose '00, 01 10, 11' equally likely

$$PAL = \frac{\text{number of faulty outputs that generate gold signature}}{\text{total number of faulty outputs}}$$

**ANS:**





# BIST Part 2

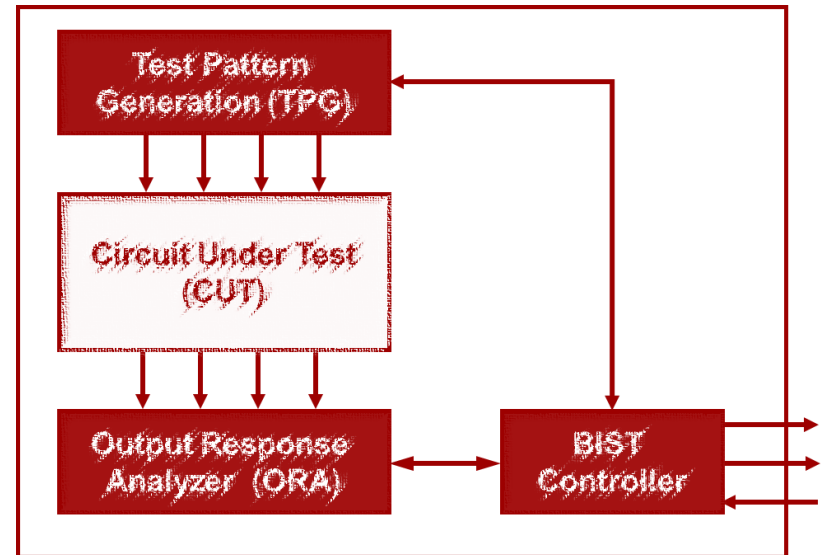
- Output Response Analysis

- ◆ Simple ORA

- \* Duplication, Reverse operation
- \* Checksum (aka. Parity Checker)
- \* Ones counter
- \* Transition counter

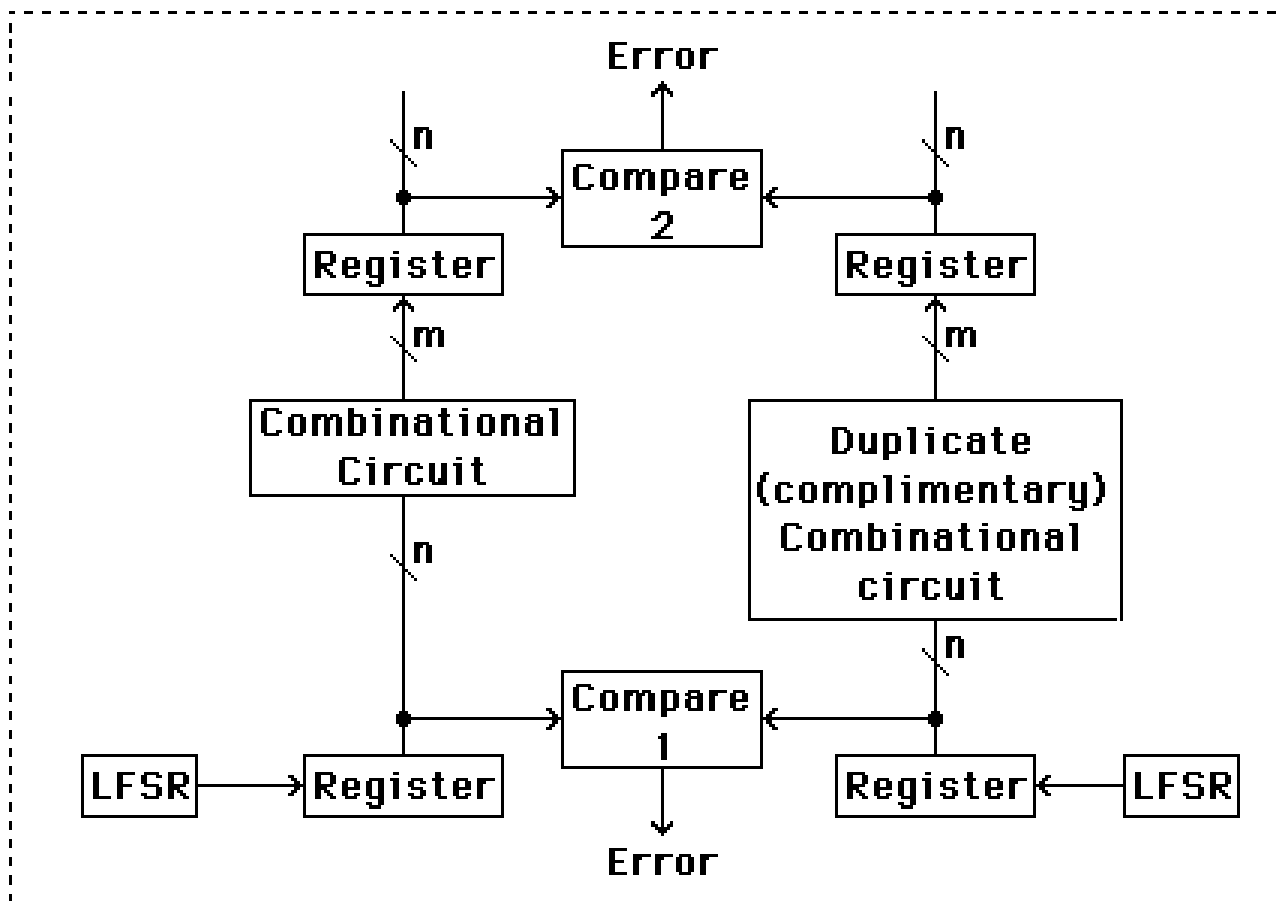
- ◆ LFSR-based

- BIST Architecture
- Issues with BIST
- Conclusions



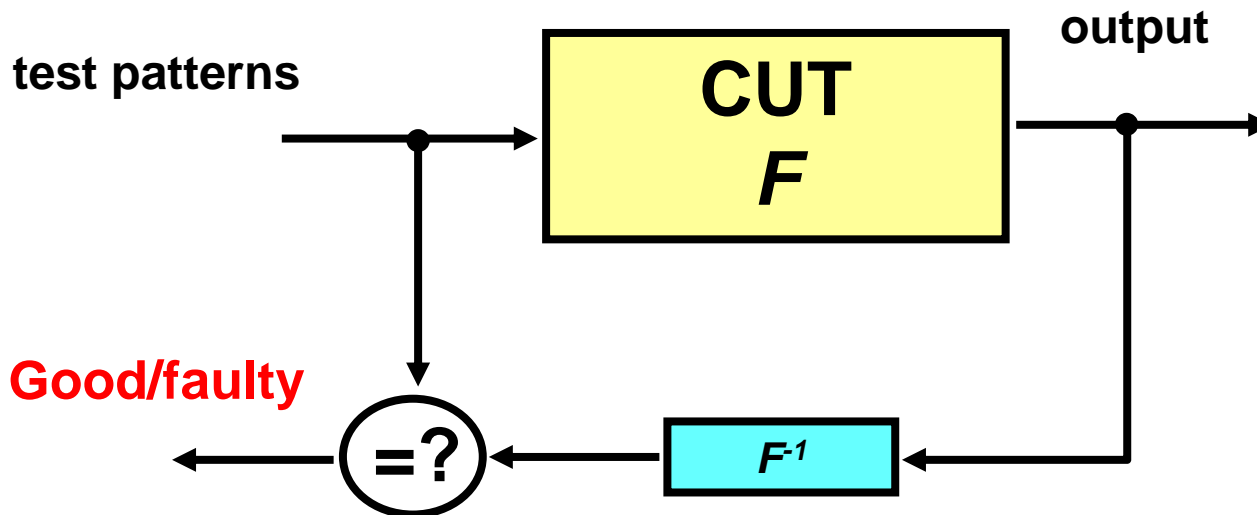
# Duplication

- Advantage: low aliasing; good for on-line BIST
- Disadvantages: too big in area



# Reverse Operation

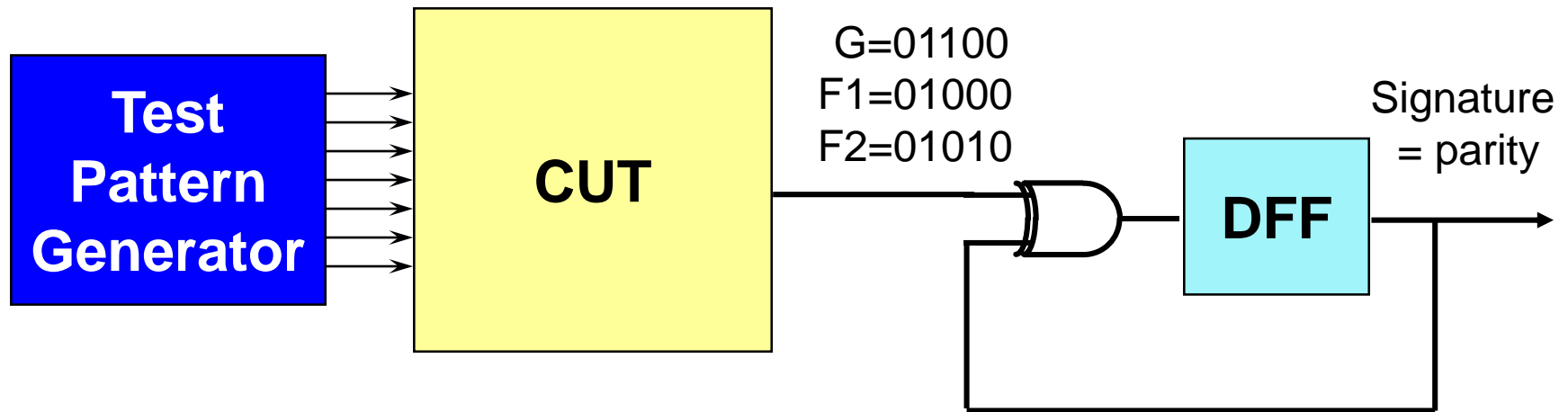
- Advantages
  - ♦ Applicable to both on-line and off-line BIST
  - ♦ Low aliasing
- Disadvantages
  - ♦ Not generally applicable to all CUT



$F^{-1}$  is reverse operation of  $F$

# Parity Checker

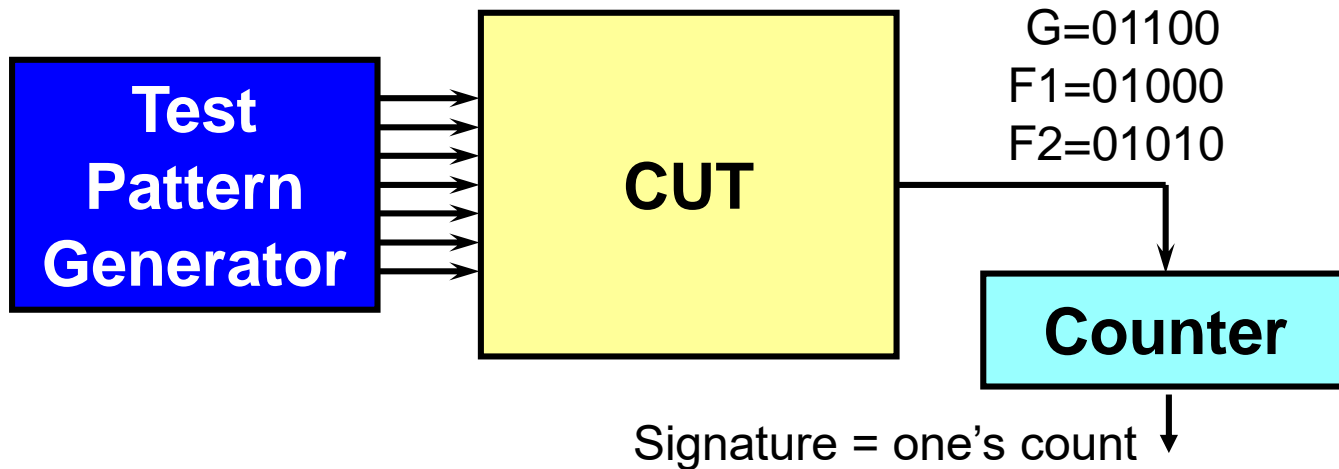
- Signature = Inversion parity of CUT output
  - ♦ Odd or even
- Example (initially DFF=0)
  - ♦ Good CUT output = 01100 → 0 gold signature
  - ♦ Faulty CUT1 output = 01000 → 1 detected, **no aliasing**
  - ♦ Faulty CUT2 output = 01010 → 0 not detected, **aliasing**



$$PAL = \frac{\text{number of faulty outputs that generate gold signature}}{\text{total number of faulty outputs}} = \frac{16-1}{2^5-1} = \frac{15}{31}$$

# Ones Counter

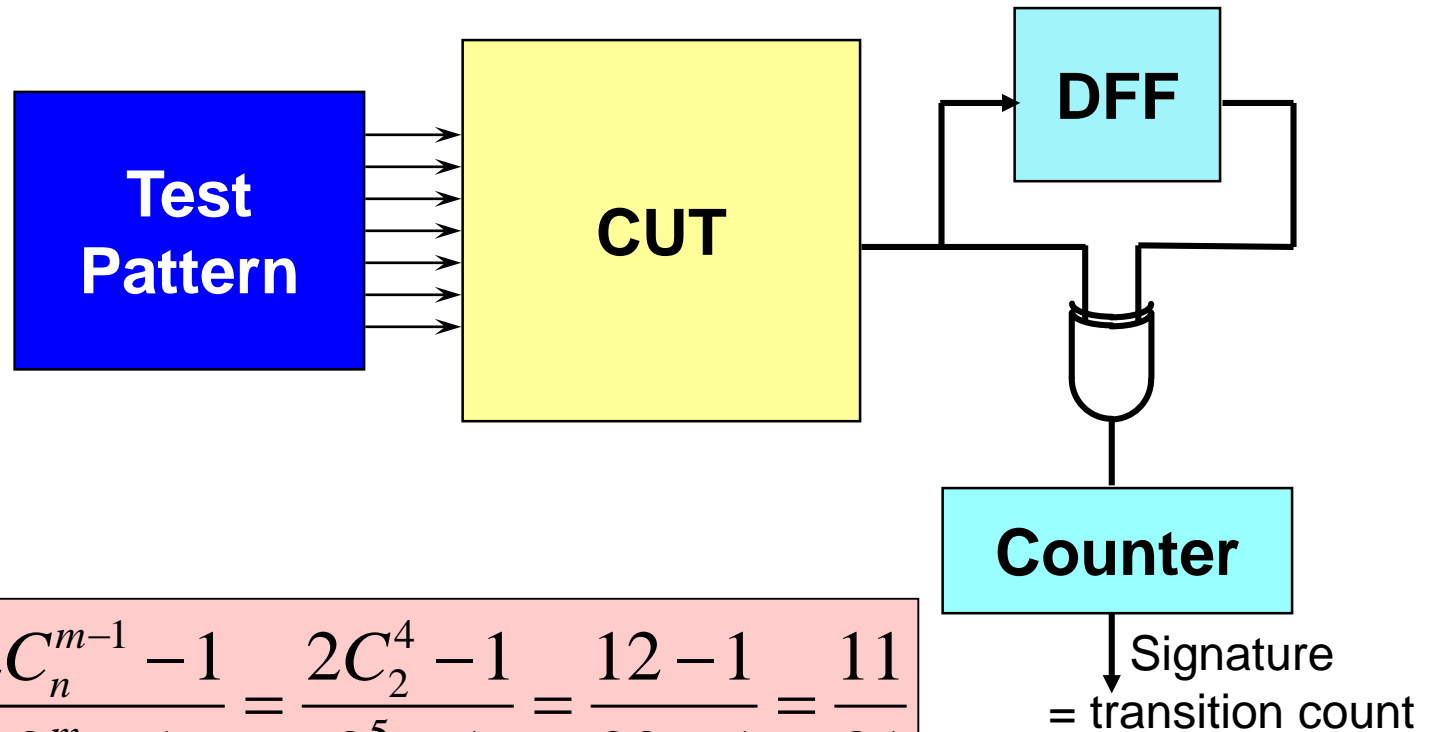
- Signature = number of ones
- Example: **sequence length=5=m; signature=2=n;**
  - ♦ Good CUT output = 01100 → 2 gold signature
  - ♦ Faulty CUT1 output = 01000 → 1 detected, **no aliasing**
  - ♦ Faulty CUT2 output = 01010 → 2 not detected, **aliasing**



$$PAL = \frac{C_n^m - 1}{2^m - 1} = \frac{C_2^5 - 1}{2^5 - 1} = \frac{10 - 1}{32 - 1} = \frac{9}{31}$$

# Transition Counter

- Signature = number of **transitions** ( $0 \rightarrow 1$ ,  $1 \rightarrow 0$ )
- Example: **sequence length**=5= $m$ ; **signature**=2= $n$ ;
  - ♦ Good CUT output = 01100  $\rightarrow$  2
  - ♦ Faulty CUT1 output = 01000  $\rightarrow$  2 not detected, **aliasing**
  - ♦ Faulty CUT2 output = 01010  $\rightarrow$  4 detected, **no aliasing**



$$PAL = \frac{2C_n^{m-1} - 1}{2^m - 1} = \frac{2C_2^4 - 1}{2^5 - 1} = \frac{12 - 1}{32 - 1} = \frac{11}{31}$$

# Summary

- Output Response Analyzer
  - ◆ Compress CUT output responses into **signatures**
  - ◆ Aliasing mean **faulty outputs compressed into gold signature**
    - \* induces **test escape**
  - ◆ Probability of aliasing (**PAL**)

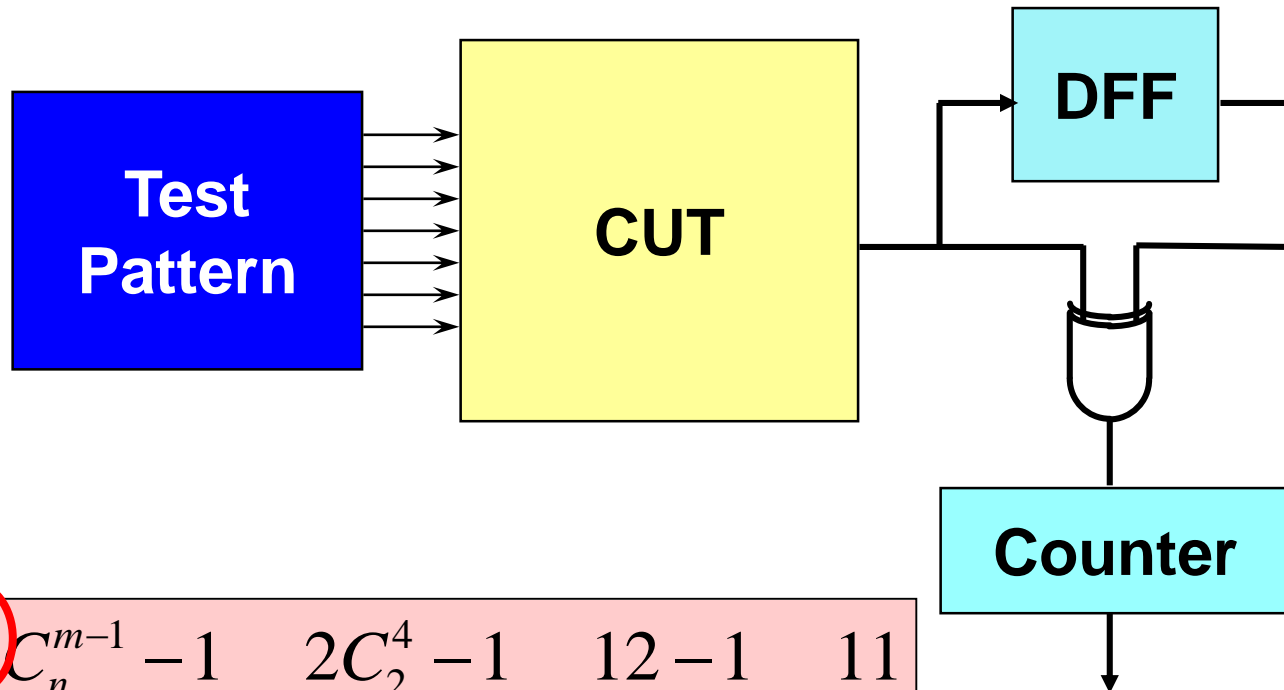
$$PAL = \frac{\text{number of faulty outputs that generate gold signature}}{\text{total number of faulty outputs}}$$

- ◆ Simple ORA
  - \* Duplication
  - \* Parity Checker
  - \* Ones counter
  - \* Transition counter

**These ORA not Good Enough**

# FFT: Transition Counter

- Q: Why factor of 2 in PAL?



$$PAL = \frac{2C_n^{m-1} - 1}{2^m - 1} = \frac{2C_2^4 - 1}{2^5 - 1} = \frac{12 - 1}{32 - 1} = \frac{11}{31}$$